



February 2007
FRFET™

FQP10N60CF / FQPF10N60CF 600V N-Channel MOSFET

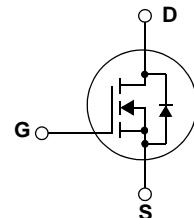
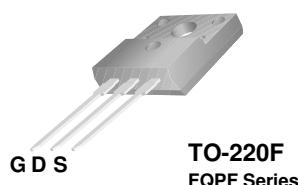
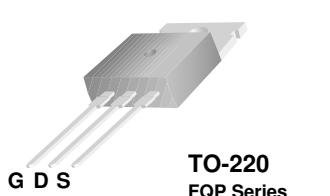
Features

- 9A, 600V, $R_{DS(on)} = 0.8\Omega$ @ $V_{GS} = 10$ V
- Low gate charge (typical 44 nC)
- Low Crss (typical 18 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.



Absolute Maximum Ratings

Symbol	Parameter	FQP10N60CF	FQPF10N60CF	Units
V_{DSS}	Drain-Source Voltage	600		V
I_D	Drain Current - Continuous ($T_C = 25^\circ C$)	9.0	9.0 *	A
	- Continuous ($T_C = 100^\circ C$)	5.7	5.7 *	A
I_{DM}	Drain Current - Pulsed	(Note 1)	36	A
V_{GSS}	Gate-Source Voltage		± 30	V
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	583	mJ
I_{AR}	Avalanche Current	(Note 1)	9.0	A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	16.9	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P_D	Power Dissipation ($T_C = 25^\circ C$)	169	50	W
	- Derate above $25^\circ C$	1.35	0.4	W/ $^\circ C$
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	$^\circ C$
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	$^\circ C$

* Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	FQP10N60CF	FQPF10N60CF	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.74	2.5	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	$^\circ C/W$

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQP10N60CF	FQP10N60CF	TO-220	--	--	50
FQPF10N60CF	FQPF10N60CF	TO-220F	--	--	50

Electrical Characteristics

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units	
Off Characteristics							
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$	600	--	--	V	
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C	--	0.7	--	$^\circ\text{C}$	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 600 \text{ V}$, $V_{\text{GS}} = 0 \text{ V}$	--	--	10	μA	
		$V_{\text{DS}} = 480 \text{ V}$, $T_C = 125^\circ\text{C}$	--	--	100	μA	
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = 30 \text{ V}$, $V_{\text{DS}} = 0 \text{ V}$	--	--	100	nA	
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = -30 \text{ V}$, $V_{\text{DS}} = 0 \text{ V}$	--	--	-100	nA	
On Characteristics							
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 250 \mu\text{A}$	2.0	--	4.0	V	
$R_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = 10 \text{ V}$, $I_D = 4.5 \text{ A}$	--	0.61	0.8	Ω	
g_{FS}	Forward Transconductance	$V_{\text{DS}} = 40 \text{ V}$, $I_D = 4.5 \text{ A}$	(Note 4)	--	8.0	--	S
Dynamic Characteristics							
C_{iss}	Input Capacitance	$V_{\text{DS}} = 25 \text{ V}$, $V_{\text{GS}} = 0 \text{ V}$, $f = 1.0 \text{ MHz}$	--	1570	2040	pF	
C_{oss}	Output Capacitance		--	166	215	pF	
C_{rss}	Reverse Transfer Capacitance		--	18	24	pF	
Switching Characteristics							
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}} = 300 \text{ V}$, $I_D = 9.0 \text{ A}$, $R_G = 25 \Omega$	--	23	55	ns	
t_r	Turn-On Rise Time		--	69	150	ns	
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	144	300	ns	
t_f	Turn-Off Fall Time		--	77	165	ns	
Q_g	Total Gate Charge	$V_{\text{DS}} = 480 \text{ V}$, $I_D = 9.0 \text{ A}$, $V_{\text{GS}} = 10 \text{ V}$	--	44	57	nC	
Q_{gs}	Gate-Source Charge		--	6.7	--	nC	
Q_{gd}	Gate-Drain Charge		--	18.5	--	nC	
Drain-Source Diode Characteristics and Maximum Ratings							
I_S	Maximum Continuous Drain-Source Diode Forward Current	--	--	9.0	A		
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	36	A		
V_{SD}	Drain-Source Diode Forward Voltage	$V_{\text{GS}} = 0 \text{ V}$, $I_S = 9.0 \text{ A}$	--	--	1.4	V	
t_{rr}	Reverse Recovery Time	$V_{\text{GS}} = 0 \text{ V}$, $I_S = 9.0 \text{ A}$, $dI_F / dt = 100 \text{ A}/\mu\text{s}$	--	90	--	ns	
Q_{rr}	Reverse Recovery Charge		--	0.3	--	μC	

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. $L = 13.2\text{mH}$, $I_{AS} = 9.0 \text{ A}$, $V_{DD} = 50 \text{ V}$, $R_G = 25 \Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq 9.0 \text{ A}$, $di/dt \leq 200 \text{ A}/\mu\text{s}$, $V_{DD} \leq \text{BV}_{\text{DSS}}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width $\leq 300 \mu\text{s}$, Duty cycle $\leq 2\%$
5. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

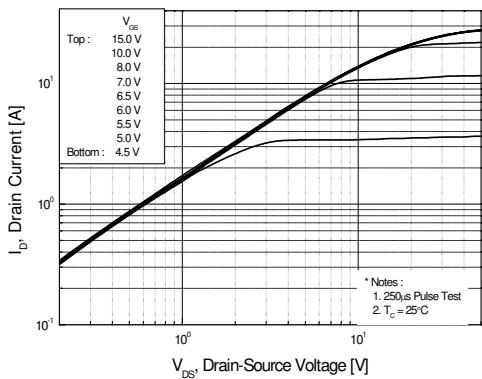


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

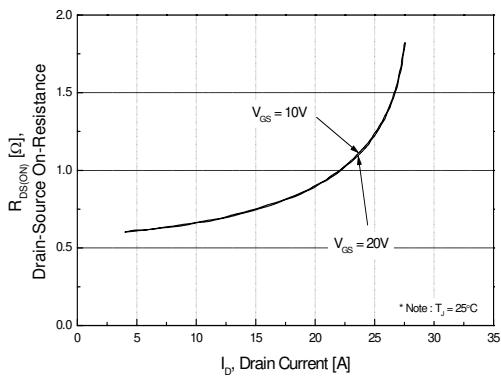


Figure 2. Transfer Characteristics

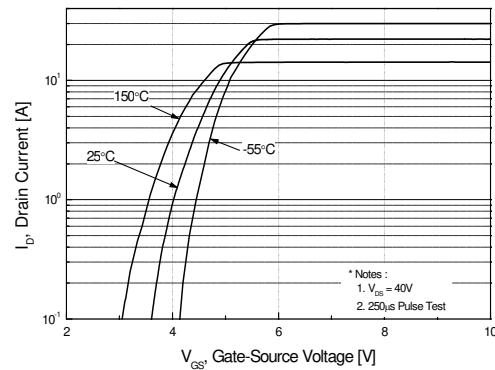


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

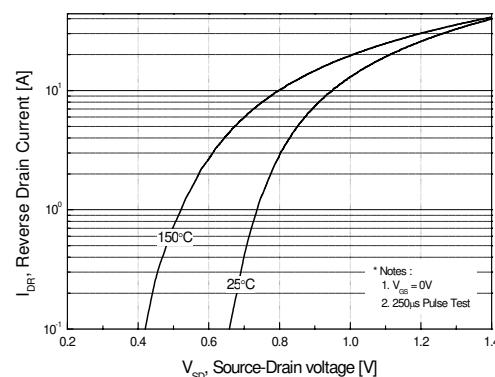


Figure 5. Capacitance Characteristics

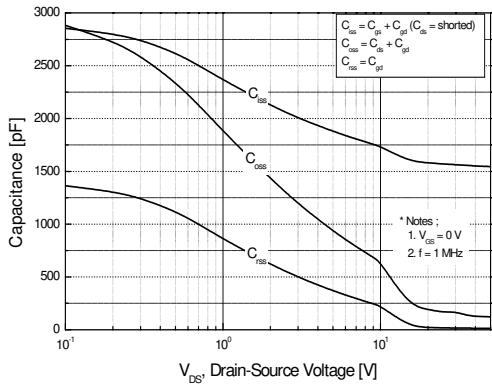
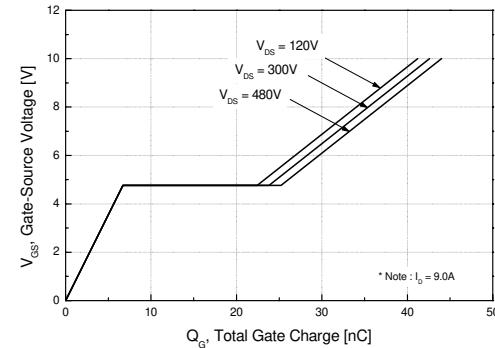


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

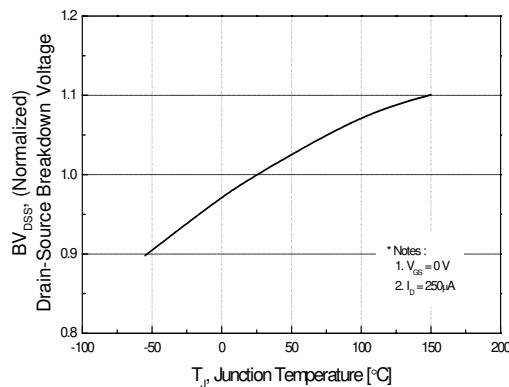


Figure 8. On-Resistance Variation vs. Temperature

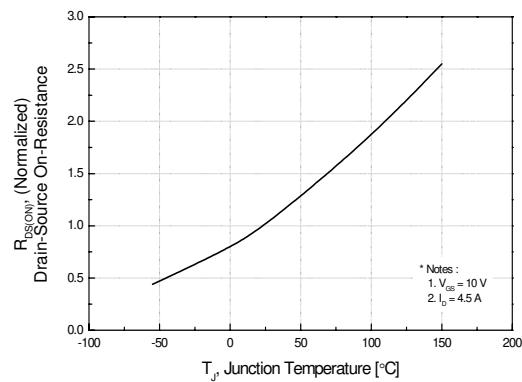


Figure 9-1. Maximum Safe Operating Area for FQP10N60C

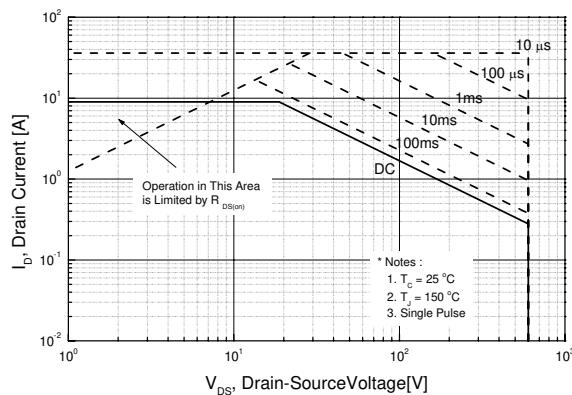


Figure 9-2. Maximum Safe Operating Area for FQPF10N60C

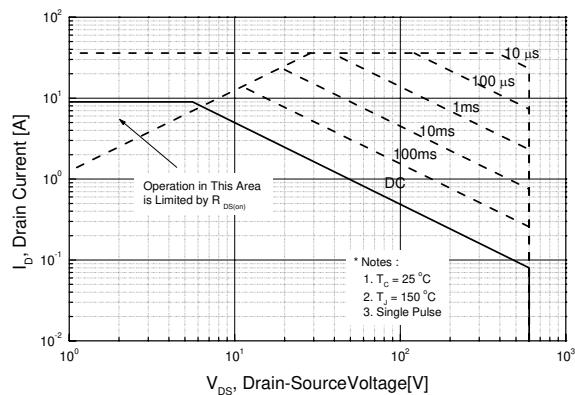
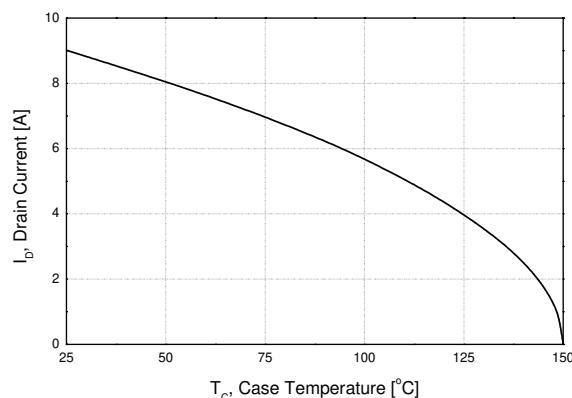


Figure 10. Maximum Drain Current vs. Case Temperature



Typical Performance Characteristics (Continued)

Figure 11-1. Transient Thermal Response Curve for FQP10N60CF

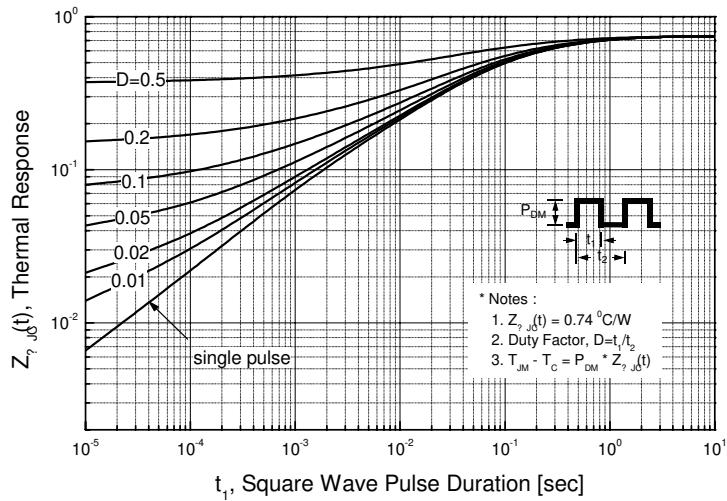
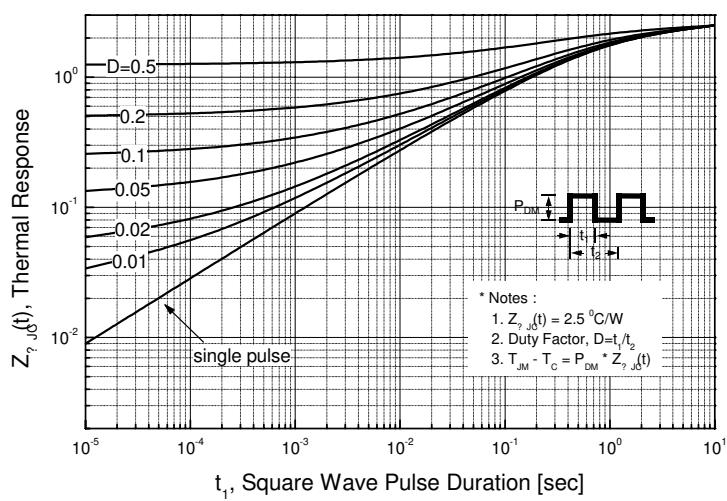
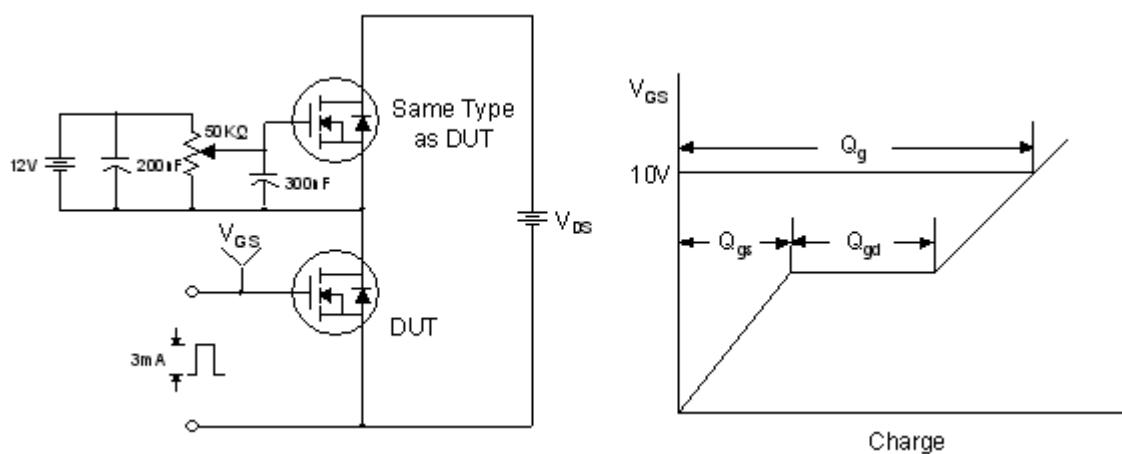


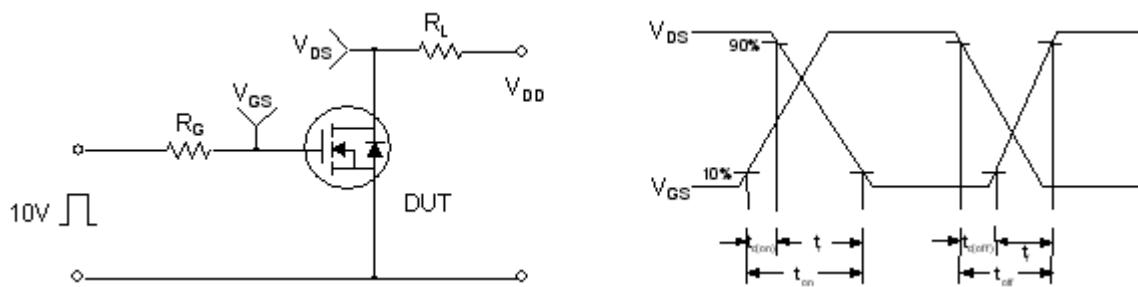
Figure 11-2. Transient Thermal Response Curve for FQPF10N60CF



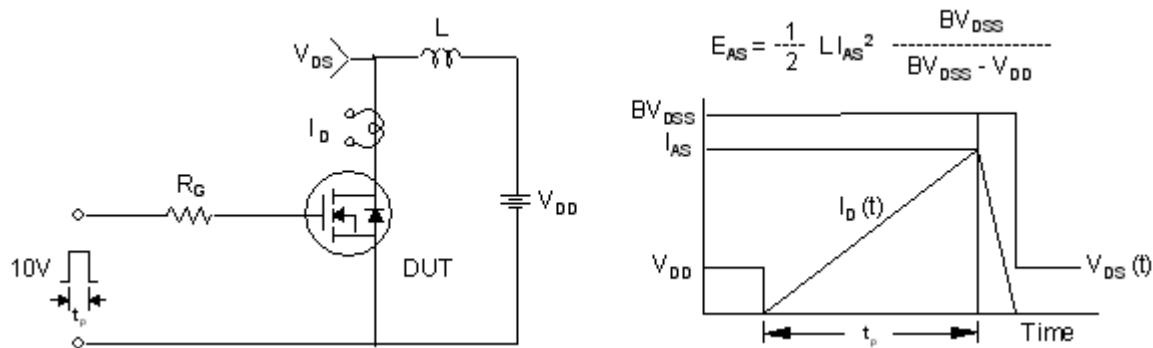
Gate Charge Test Circuit & Waveform



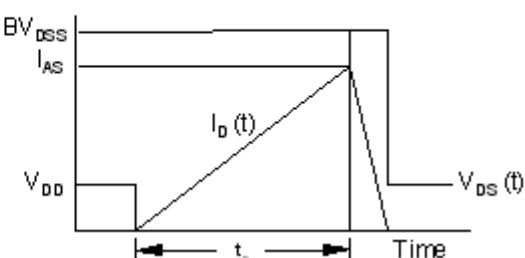
Resistive Switching Test Circuit & Waveforms



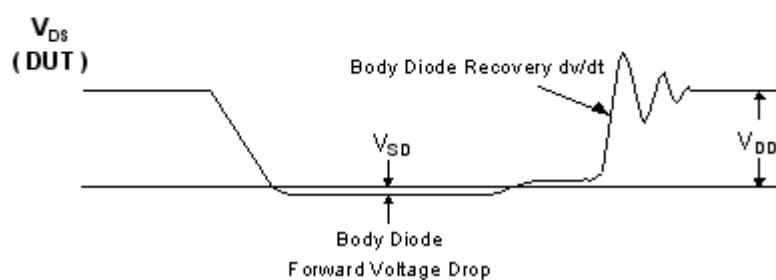
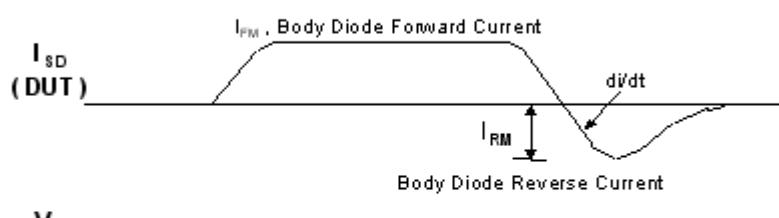
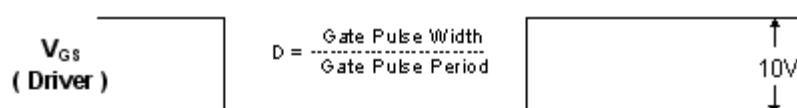
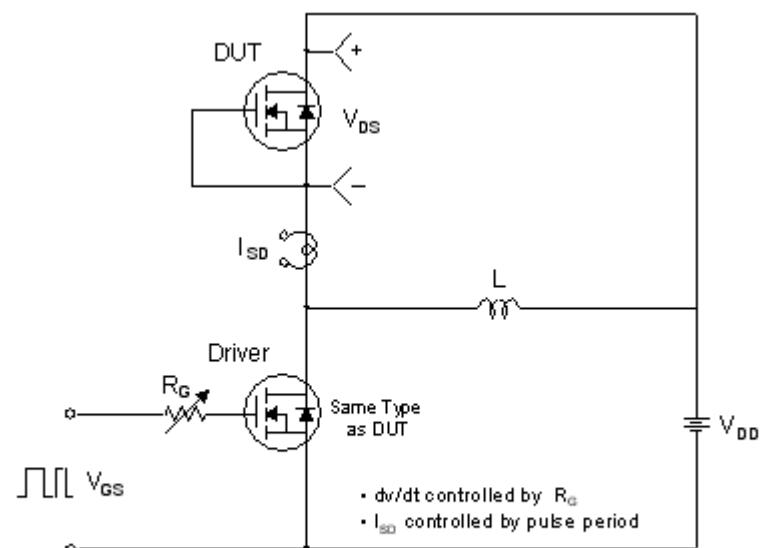
Unclamped Inductive Switching Test Circuit & Waveforms



$$E_{AS} = \frac{1}{2} L I_{AS}^2 - \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$

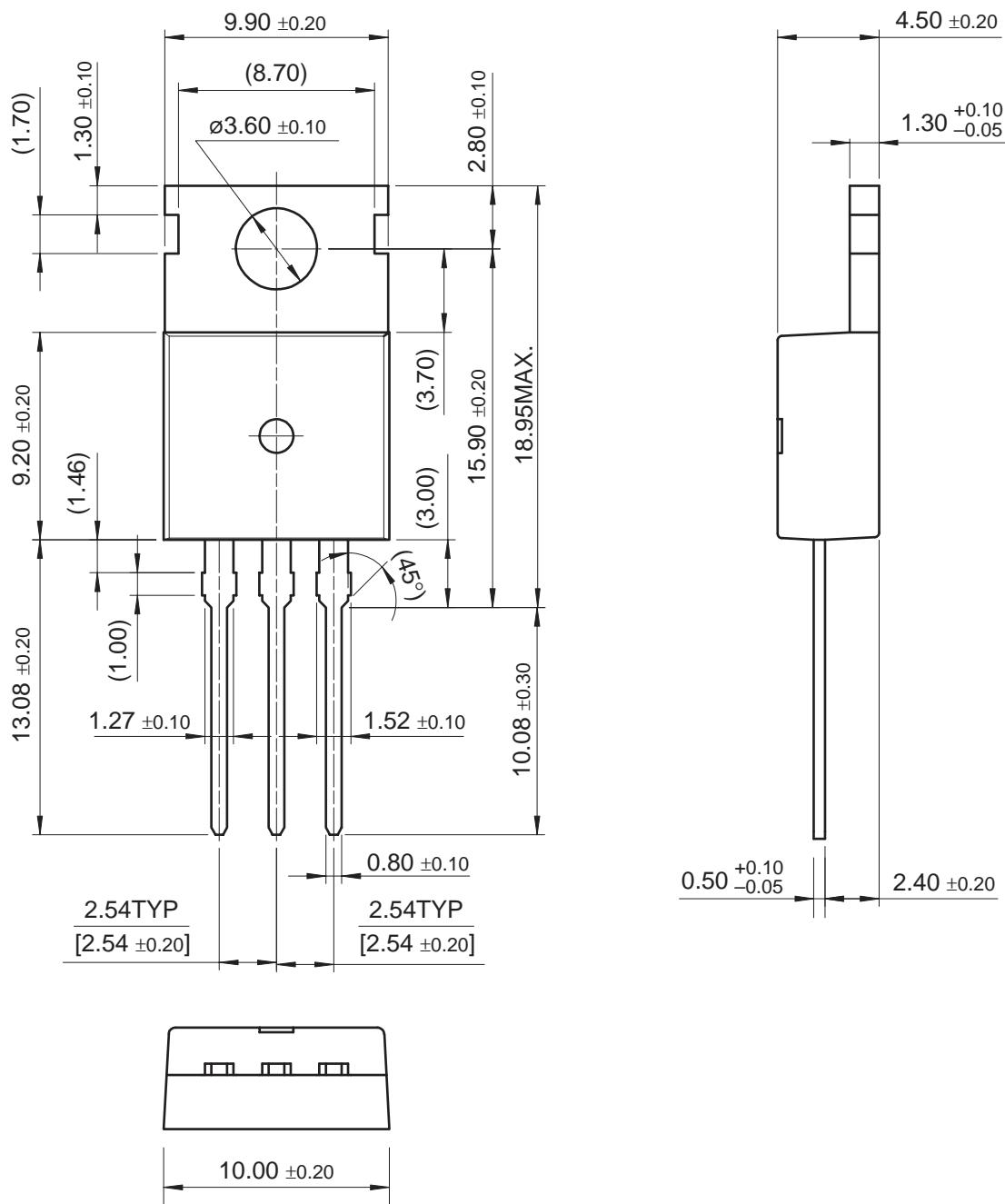


Peak Diode Recovery dv/dt Test Circuit & Waveforms



Mechanical Dimensions

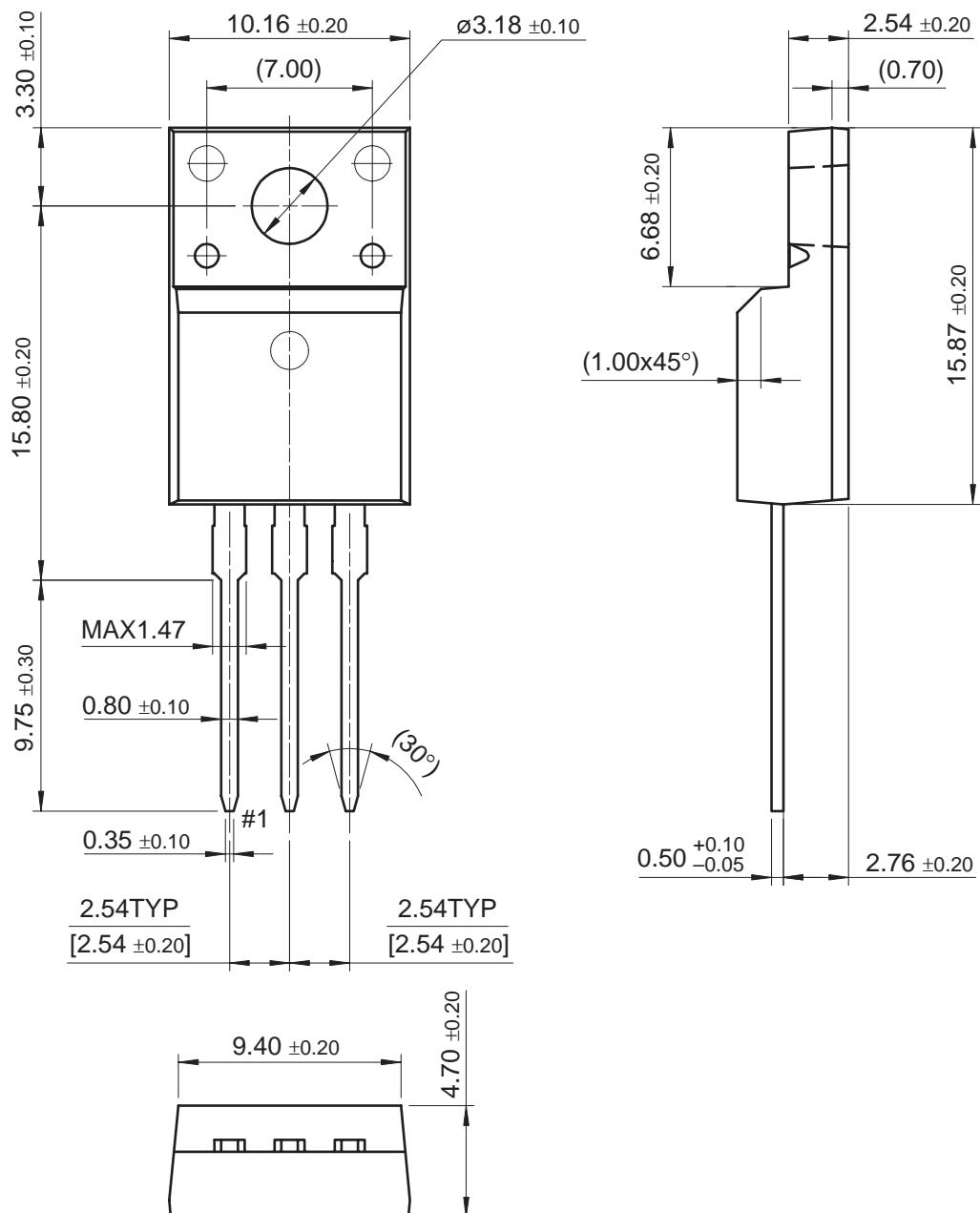
TO-220



Dimensions in Millimeters

Mechanical Dimensions (Continued)

TO-220F



Dimensions in Millimeters

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